

# **MOSFET**

# StronglRFET<sup>™</sup>2 Power-Transistor

#### **Features**

- Optimized for wide range of applications
- N-channel, normal level100% avalanche tested

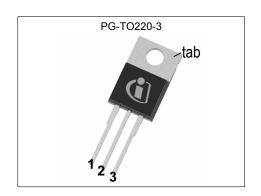
- Pb-free lead plating; RoHS compliant
  Halogen-free according to IEC61249-2-21

#### **Product validation**

Qualified according to JEDEC Standard

Table 1 **Key Performance Parameters** 

Table 1 1to 1 to 1 to 1 to 1 to 1 to 1 to 1								
Parameter	Value	Unit						
<b>V</b> <sub>DS</sub>	60	V						
R <sub>DS(on),max</sub>	1.9	mΩ						
I <sub>D</sub>	185	A						
Qoss	108	nC						
Q <sub>G</sub> (0V10V)	108	nC						











Type / Ordering Code	Package	Marking	Related Links
IPP019N06NF2S	PG-TO220-3	019N06NS	-

# StrongIRFET<sup>TM</sup>2 Power-Transistor IPP019N06NF2S



## **Table of Contents**

Description	1
Maximum ratings	3
Thermal characteristics	3
Electrical characteristics	4
Electrical characteristics diagrams	6
Package Outlines	0
Revision History	1
Trademarks 1	1
Disclaimer	1

### StrongIRFET<sup>™</sup>2 Power-Transistor IPP019N06NF2S



# 1 Maximum ratings at $T_A$ =25 °C, unless otherwise specified

Table 2 Maximum ratings

Davamatav	Cymahal		Value	S			
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous drain current <sup>1)</sup>	I <sub>D</sub>	- - -	- - -	185 142 33	A	$V_{GS}$ =10 V, $T_{C}$ =25 °C $V_{GS}$ =10 V, $T_{C}$ =100 °C $V_{GS}$ =10 V, $T_{A}$ =25 °C, $R_{thJA}$ =40 °C/W <sup>2</sup> )	
Pulsed drain current <sup>3)</sup>	I <sub>D,pulse</sub>	-	-	740	Α	T <sub>C</sub> =25 °C	
Avalanche energy, single pulse <sup>4)</sup>	<b>E</b> AS	-	-	349	mJ	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 $\Omega$	
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-	
Power dissipation	P <sub>tot</sub>	-	-	188 3.8	W	T <sub>C</sub> =25 °C T <sub>A</sub> =25 °C, R <sub>thJA</sub> =40 °C/W <sup>2</sup> )	
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55	-	175	°C	-	

#### 2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Cumbal	Values			Unit	Note / Took Condition
Parameter	Symbol	Min.	Тур.	Max.	Ullit	Note / Test Condition
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	8.0	°C/W	-
Thermal resistance, junction - ambient, 6 cm² cooling area²)		-	-	40	°C/W	-
Thermal resistance, junction - ambient, minimal footprint	R <sub>thJA</sub>	-	-	62	°C/W	-

<sup>&</sup>lt;sup>1)</sup> Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.  $^{2)}$  Device on 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain

connection. PCB is vertical in still air.

3) See Diagram 3 for more detailed information

<sup>&</sup>lt;sup>4)</sup> See Diagram 13 for more detailed information

# StrongIRFET<sup>™</sup>2 Power-Transistor IPP019N06NF2S



### **Electrical characteristics**

at  $T_j$ =25 °C, unless otherwise specified

Table 4 **Static characteristics** 

Barranatan	0	Values					
Parameter	Symbol	Min.	Min. Typ. Ma		Unit	Note / Test Condition	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	60	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	
Gate threshold voltage	V <sub>GS(th)</sub>	2.1	2.8	3.3	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 129 \ \mu {\rm A}$	
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.5 10	1 100	μΑ	V <sub>DS</sub> =60 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =60 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	
Gate-source leakage current	I <sub>GSS</sub>	-	10	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	
Drain-source on-state resistance <sup>1)</sup>	R <sub>DS(on)</sub>	-	1.7 2.1	1.9 2.9	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =100 A V <sub>GS</sub> =6 V, I <sub>D</sub> =50 A	
Gate resistance	R <sub>G</sub>	-	2.7	-	Ω	-	
Transconductance <sup>2)</sup>	<b>g</b> fs	110	-	-	S	$ V_{DS}  \ge 2 I_D R_{DS(on)max}, I_D = 100 A$	

Table 5 **Dynamic characteristics** 

Paramatan	Oh a l	Values			11:4	Nata (Tant Oam dition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance	C <sub>iss</sub>	-	7300	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =30 V, f=1 MHz
Output capacitance	Coss	-	1550	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =30 V, f=1 MHz
Reverse transfer capacitance	C <sub>rss</sub>	-	63	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =30 V, f=1 MHz
Turn-on delay time	$t_{\sf d(on)}$	-	22	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Rise time	t <sub>r</sub>	-	31	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Turn-off delay time	$t_{ m d(off)}$	-	48	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Fall time	t <sub>f</sub>	-	17	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$

Table 6 Gate charge characteristics<sup>3)</sup>

Parameter	Symbol	Values				
		Min.	Тур.	Max.	Unit	Note / Test Condition
Gate to source charge	Q <sub>gs</sub>	-	33	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge at threshold	$Q_{g(th)}$	-	20	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate to drain charge	$Q_{ m gd}$	-	20	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Switching charge	Q <sub>sw</sub>	-	33	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total <sup>2)</sup>	Qg	-	108	162	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate plateau voltage	V <sub>plateau</sub>	-	4.5	-	V	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total, sync. FET	Q <sub>g(sync)</sub>	-	100	-	nC	V <sub>DS</sub> =0.1 V, V <sub>GS</sub> =0 to 10 V
Output charge	Q <sub>oss</sub>	-	108	-	nC	V <sub>DS</sub> =30 V, V <sub>GS</sub> =0 V

<sup>&</sup>lt;sup>1)</sup> R<sub>DS(on)</sub> is specified at a distance of 1.8 mm distance to the package body; mounting at a larger distance increases the overallpackage resistance of approximately 0.04 mOhm/mm per leg.
<sup>2)</sup> Defined by design. Not subject to production test.
<sup>3)</sup> See "Gate charge waveforms" for parameter definition

# StrongIRFET<sup>TM</sup>2 Power-Transistor IPP019N06NF2S

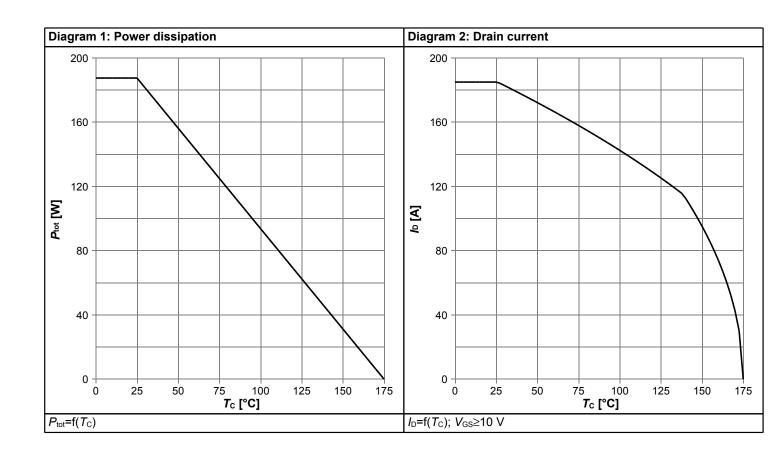


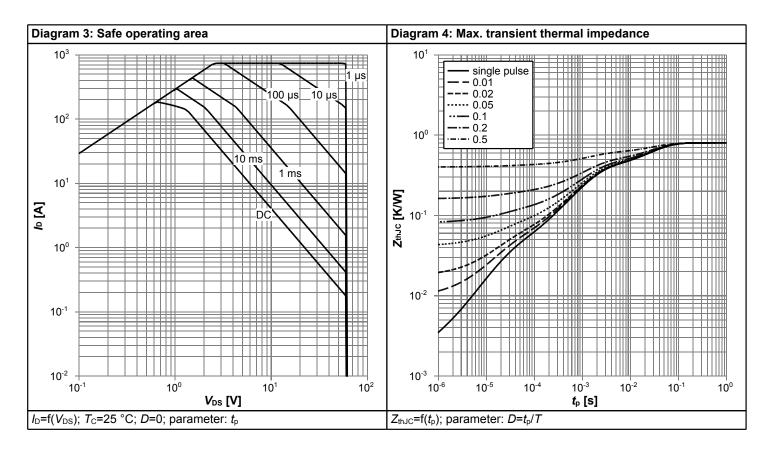
### Table 7 Reverse diode

Davamatav	Symbol		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continuous forward current	Is	-	-	144	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode pulse current	I <sub>S,pulse</sub>	-	-	740	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode forward voltage	V <sub>SD</sub>	-	0.92	1.0	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =100 A, T <sub>j</sub> =25 °C	
Reverse recovery time	t <sub>rr</sub>	-	34	-	ns	$V_R$ =30 V, $I_F$ =100 A, $di_F/dt$ =500 A/ $\mu$ s	
Reverse recovery charge	Qrr	-	169	-	nC	V <sub>R</sub> =30 V, I <sub>F</sub> =100 A, d <i>i</i> <sub>F</sub> /d <i>t</i> =500 A/μs	

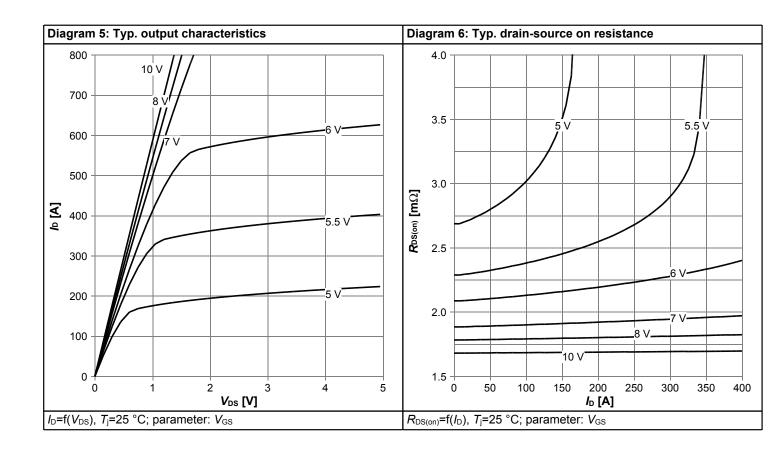


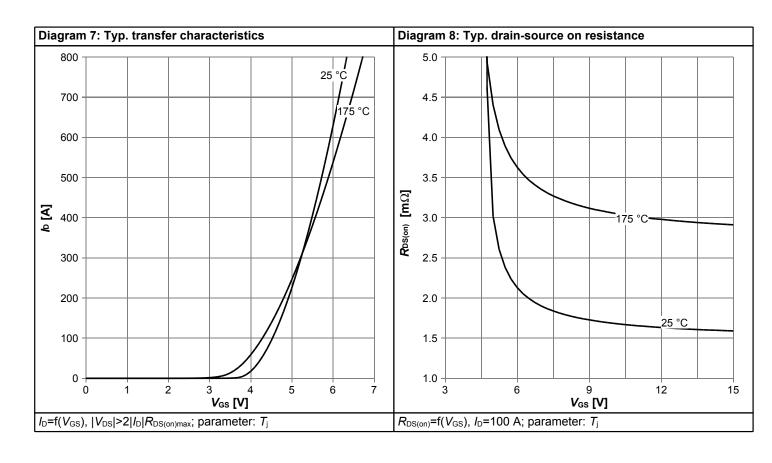
## 4 Electrical characteristics diagrams



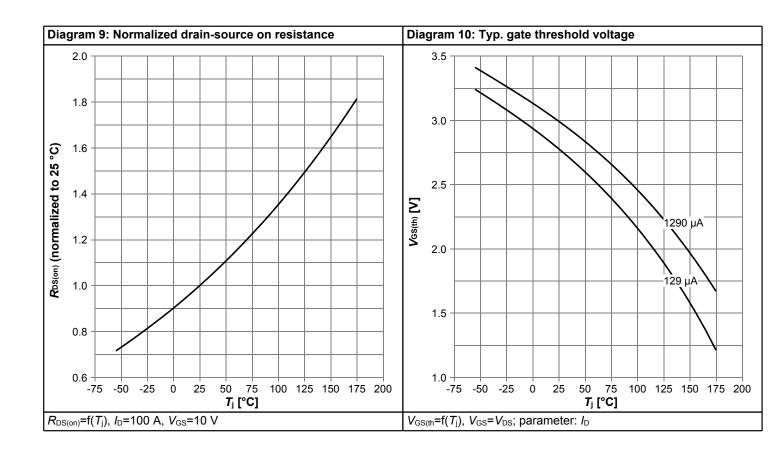


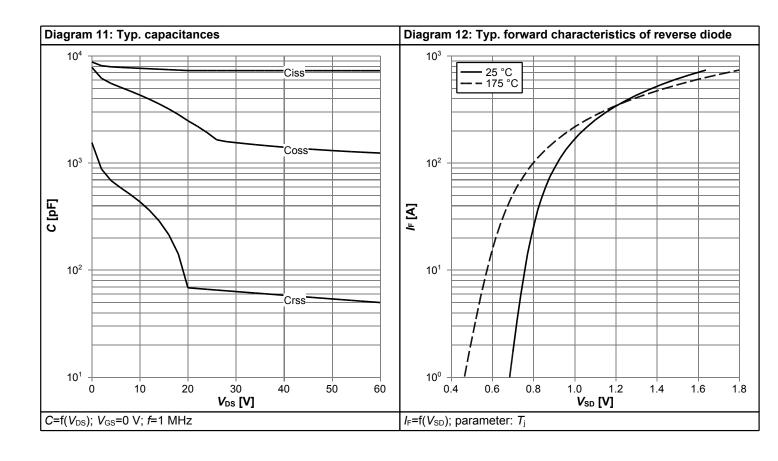




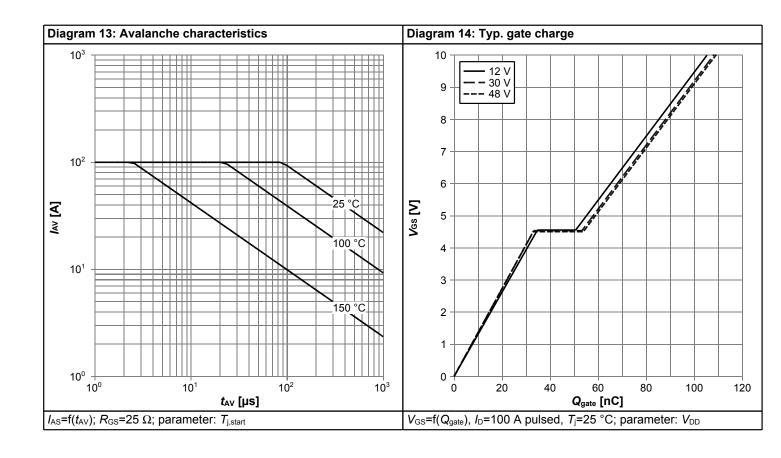


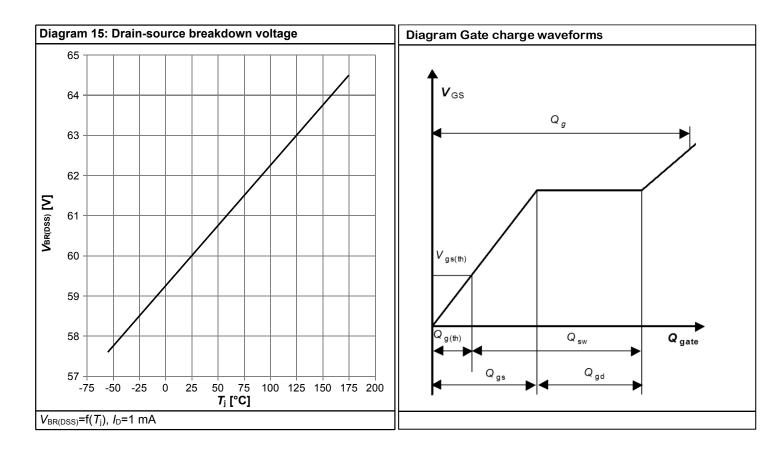














# 5 Package Outlines

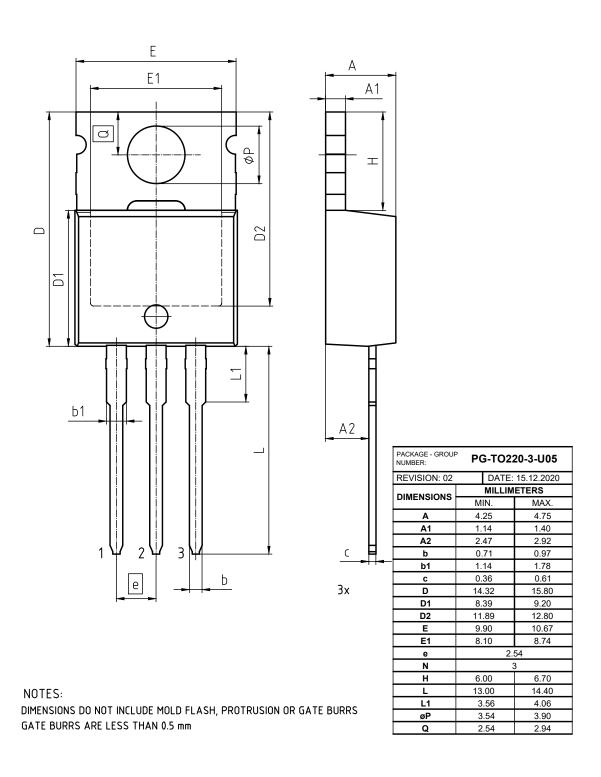


Figure 1 Outline PG-TO220-3, dimensions in mm

# StrongIRFET<sup>TM</sup>2 Power-Transistor IPP019N06NF2S



#### **Revision History**

IPP019N06NF2S

Revision: 2022-05-19, Rev. 2.1

Previous Revision

1 10110401	Toviodo (Covición							
Revision	Date	Subjects (major changes since last revision)						
2.0	2022-02-14	Release of final version						
2.1	2022-05-19	Updated diagram 12 title						

#### **Trademarks**

All referenced product or service names and trademarks are the property of their respective owners.

#### We Listen to Your Comments

Any information within this document that you feel is wrong, unclear or missing at all? Your feedback will help us to continuously improve the quality of this document. Please send your proposal (including a reference to this document) to: erratum@infineon.com

Published by Infineon Technologies AG 81726 München, Germany © 2022 Infineon Technologies AG All Rights Reserved.

#### **Legal Disclaimer**

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie").

With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

#### Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office (www.infineon.com).

#### Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

The Infineon Technologies component described in this Data Sheet may be used in life-support devices or systems and/or automotive, aviation and aerospace applications or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support, automotive, aviation and aerospace device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.